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(54) **THERMOMETRY HEATING AND SENSING ASSEMBLY**

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(56) **References Cited**

U.S. PATENT DOCUMENTS

4,987,579 A 1/1991 Yoshinaka et al.
5,116,136 A 5/1992 Newman et al.
(Continued)

FOREIGN PATENT DOCUMENTS

EP 417274 A1 3/1991
EP 979394 B1 10/2001
(Continued)

OTHER PUBLICATIONS

Millonig, "Assessing and Managing Fever", University of Minnesota College of Pharmacy, Center for Leading Healthcare Change, Publication date: Nov. 9, 2012 (7 pages).

(Continued)

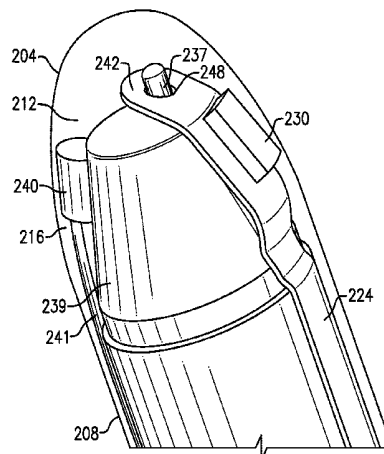
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(57) **ABSTRACT**

A thermometry apparatus includes a distal probe tip having a hollow interior. An insulating support is at least partially disposed within the interior of the distal probe tip. The insulating support is configured to receive at least one of at least one heating element and at least one temperature sensing element. According to one version, the insulating support is a flexible circuit strip configured to receive the at least one heating element(s) to protect the leads from damage and premature breakage.

12 Claims, 8 Drawing Sheets

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- (51) **Int. Cl.**
G01K 1/18 (2006.01)
G01K 13/00 (2006.01)
 2006/0106365 A1* 5/2006 Lane G01K 1/083
 604/508
 2007/0055171 A1 3/2007 Fraden
 2007/0100253 A1 5/2007 Sisk et al.
 2008/0019415 A1 1/2008 Kraus
 2008/0089387 A1 4/2008 Price
 2009/0135884 A1 5/2009 Sisk et al.
 2009/0141771 A1 6/2009 Owen et al.
 2009/0168838 A1 7/2009 Harr et al.
 2009/0285260 A1 11/2009 Stone et al.
 2011/0137201 A1 6/2011 Fraden
 2011/0249701 A1 10/2011 Bieberich et al.
 2011/0265320 A1 11/2011 Sisk et al.
 2012/0024833 A1 2/2012 Klewer et al.
 2015/0036719 A1* 2/2015 Koduri G01K 13/002
 374/152
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- (56) **References Cited**

U.S. PATENT DOCUMENTS

5,178,468 A 1/1993 Shiokawa et al.
 5,406,053 A * 4/1995 Masreliez B23K 3/0315
 219/229
 5,581,238 A 12/1996 Chang et al.
 5,632,555 A 5/1997 Gregory et al.
 5,792,070 A 8/1998 Kauphusman et al.
 6,280,397 B1 8/2001 Yarden et al.
 6,511,478 B1 1/2003 Burnside et al.
 6,547,745 B1 4/2003 Rubinstein
 6,827,487 B2 12/2004 Baumbach
 6,839,651 B2 1/2005 Lantz et al.
 6,866,391 B2 3/2005 Krausse
 6,886,978 B2 5/2005 Tokita et al.
 6,890,096 B2 5/2005 Tokita et al.
 6,976,783 B2 12/2005 Chen
 7,059,767 B2 6/2006 Tokita et al.
 7,284,904 B2 10/2007 Tokita et al.
 7,293,915 B2 11/2007 Chen
 7,299,148 B2 11/2007 Hunt et al.
 7,314,310 B2 1/2008 Medero
 7,316,507 B2 1/2008 Sisk et al.
 7,374,336 B2 5/2008 Fraden
 7,484,887 B2 2/2009 Shidemantle et al.
 7,494,274 B2 2/2009 Sisk et al.
 7,507,021 B2 3/2009 Yerlikaya et al.
 2002/0123690 A1 9/2002 Fraden
 2003/0023398 A1 1/2003 Lantz et al.
 2004/0076215 A1 4/2004 Baumbach
 2004/0254497 A1 12/2004 Fraden et al.
 2005/0220170 A1 10/2005 Tokita et al.

FOREIGN PATENT DOCUMENTS

EP 1249691 A1 10/2002
 EP 1299044 B1 6/2005
 EP 1643228 A1 4/2006
 EP 1645236 A1 4/2006
 EP 1783469 A1 5/2007
 EP 1783470 A2 5/2007
 EP 1909086 A2 4/2008
 EP 2075559 A2 7/2009
 EP 2161556 A1 3/2010
 GB 2395794 A 6/2004
 WO 2001/027580 A1 4/2001
 WO 2002/000129 A1 1/2002
 WO 2003/002965 A1 1/2003
 WO 2005/048809 A1 6/2005
 WO 2006/010108 A2 1/2006
 WO 2008/139347 A1 11/2008
 WO 2010/014354 A1 2/2010

OTHER PUBLICATIONS

Watlow® Thermal Solutions for Medical and Clinical Applications,
 2012 Watlow Electric Manufacturing Company, Publication date:
 2012 (20 pages).
 Yin et al., "Microstructure, Property and Processing of Functional
 Ceramics", Metallurgical Industry Press, Springer Berlin
 Heidelberg, 2010 (Abstract).

* cited by examiner

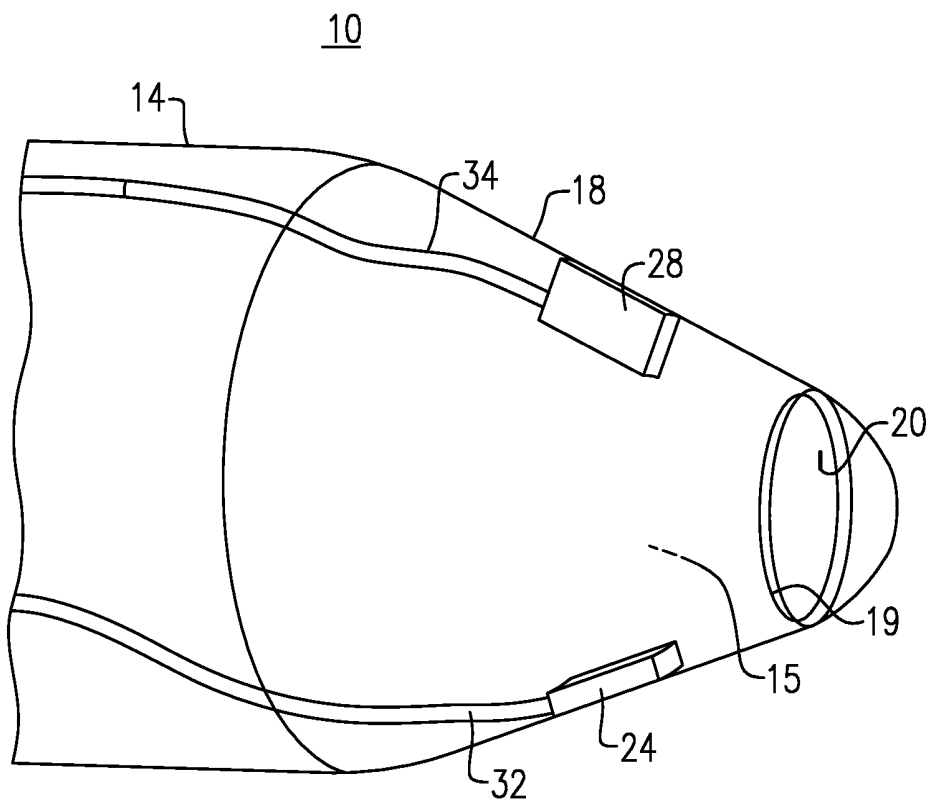
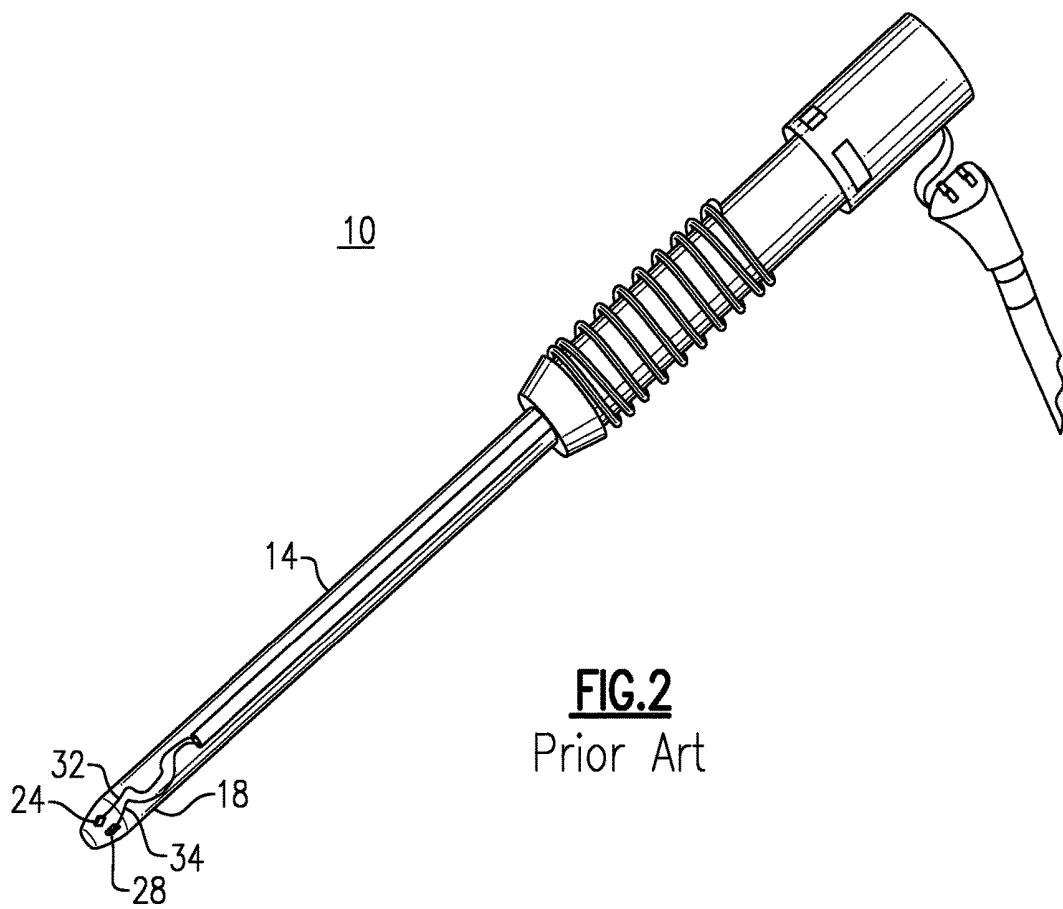


FIG. 1
Prior Art



100

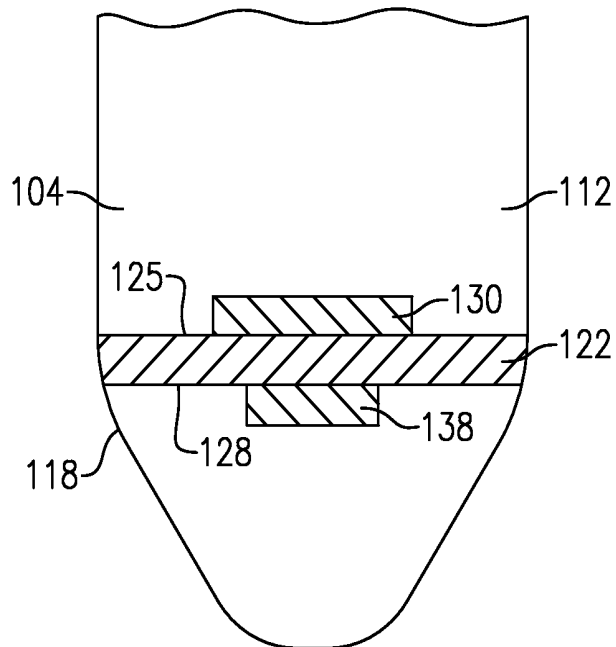


FIG.3

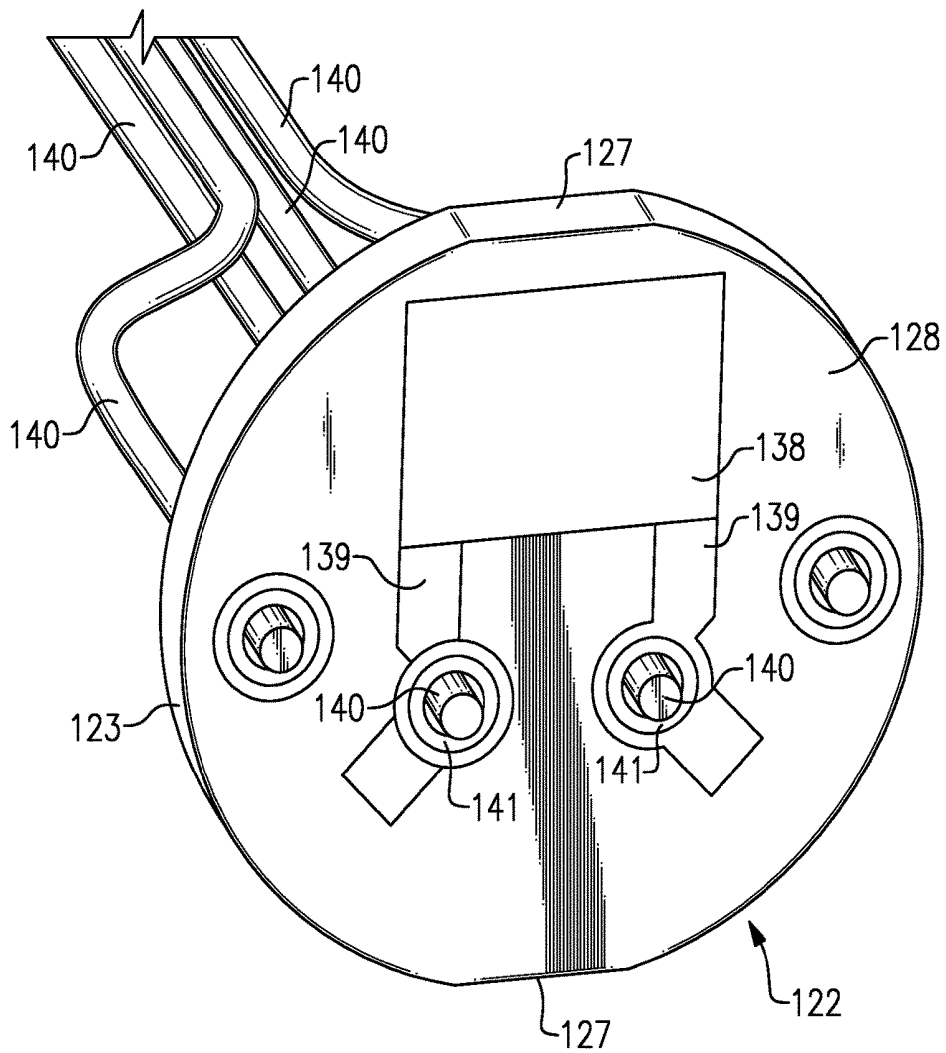
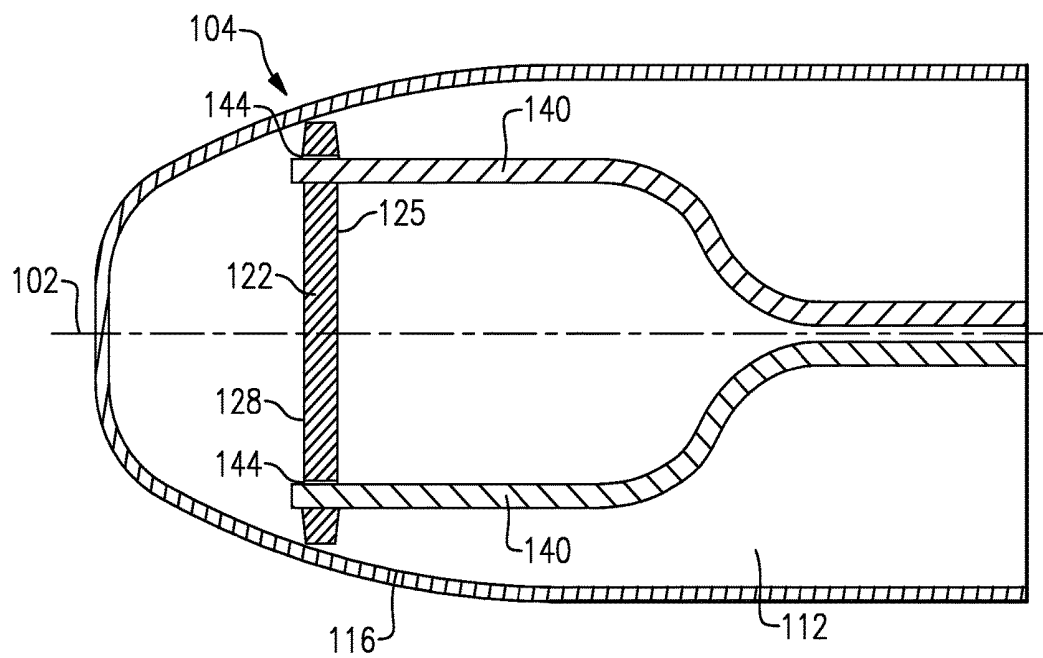


FIG.4

**FIG.5**

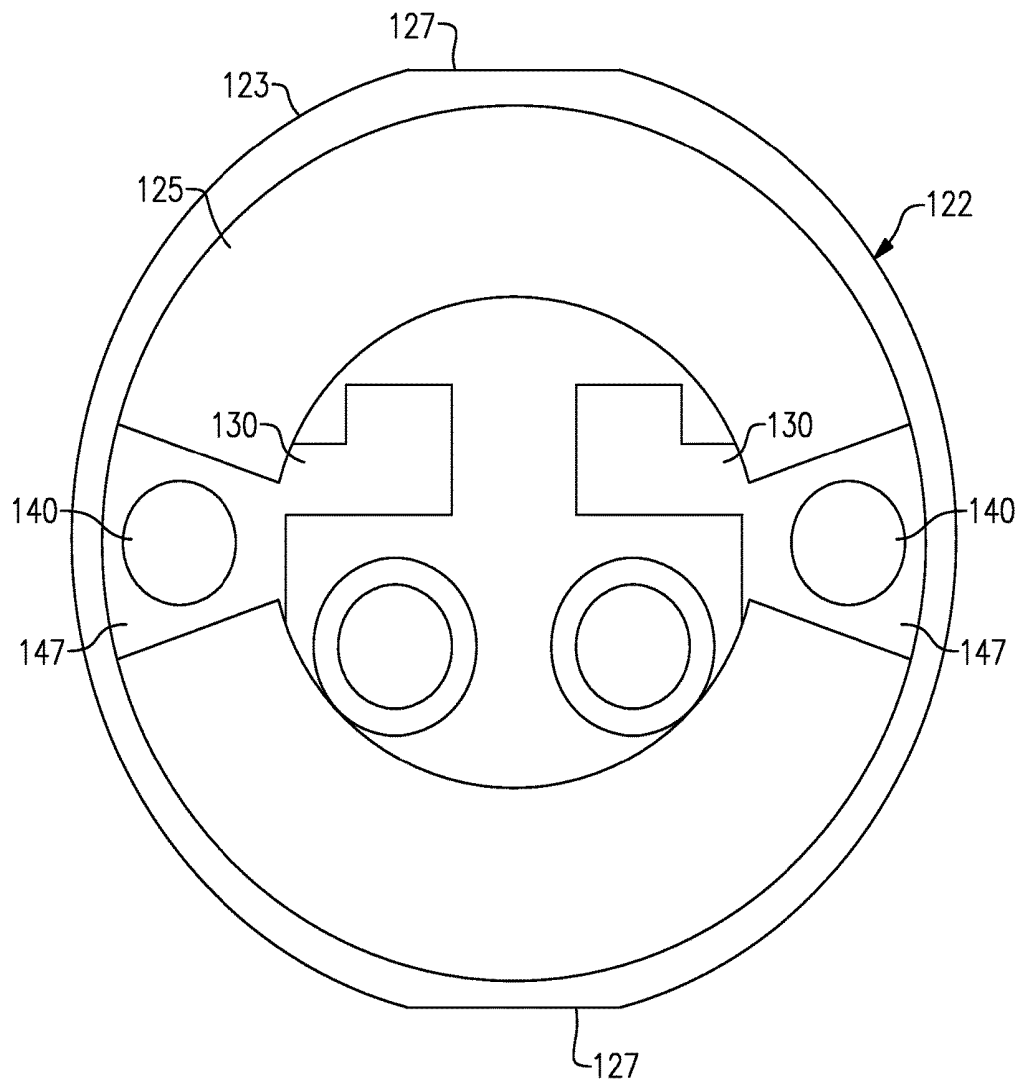
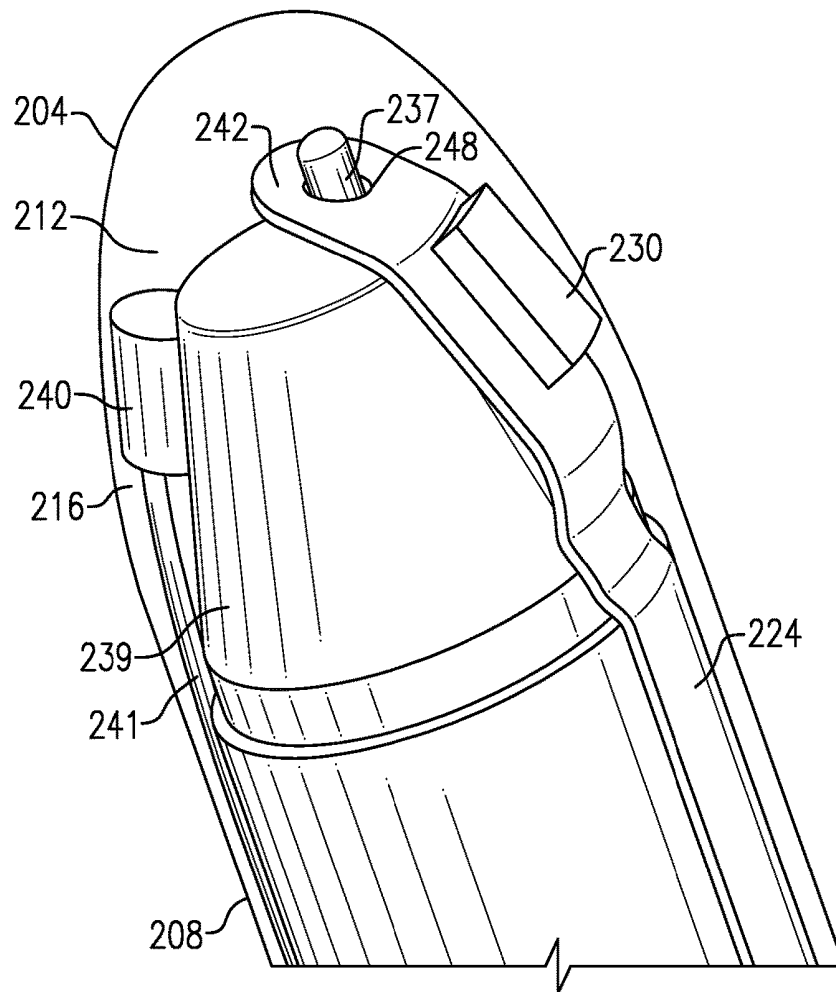
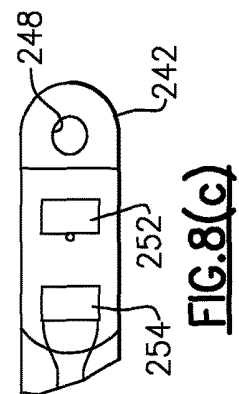
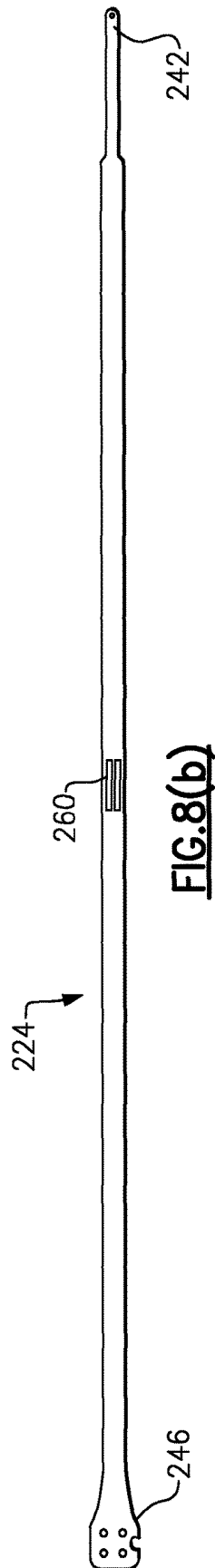
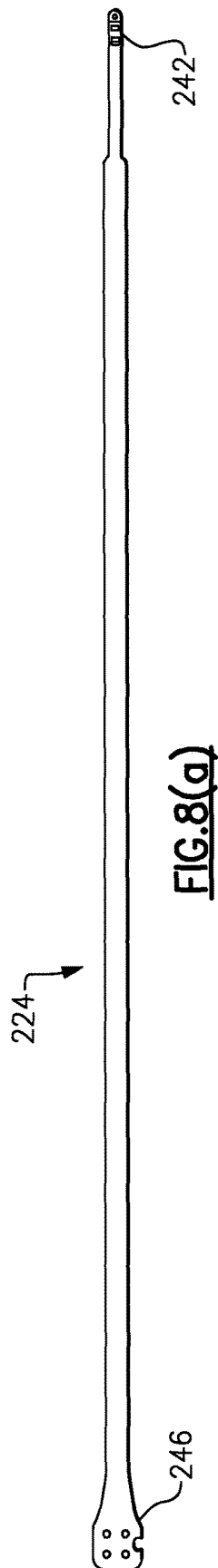


FIG. 6

200**FIG. 7**



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THERMOMETRY HEATING AND SENSING ASSEMBLY

CROSS REFERENCE TO RELATED APPLICATION

This application claims priority under relevant portions of 35 U.S.C. § 119 to U.S. Patent Application Ser. No. 61/935, 106, filed Feb. 3, 2014, and entitled: Thermometry Heating and Sensing Assembly, the entire contents of this document being incorporated by reference.

TECHNICAL FIELD

This application is generally directed to the field of medical devices and more specifically to a patient thermometry heating and sensing assembly, including an improved thermometry probe tip design.

BACKGROUND

Medical diagnostic apparatus, such as the SureTemp® thermometer manufactured and sold by Welch Allyn of Skaneateles Falls, N.Y., are known for measuring the body temperature of a patient. A probe includes a proximal end that is connected by means of a tethering cord to a device housing, the latter containing a processor and a display. The probe is defined by an elongate probe body, including a conically shaped distal probe tip that is configured to retain a temperature sensor or sensing element, as well as a heating element. The heating element is used in order to preheat the probe given the temperature differences between the environment and the core body temperature of a patient at an intended target (e.g., the axilla, rectum, sublingual pocket), so as to effectively shorten the amount of time that is required to take a temperature measurement.

A probe **14** of a prior art thermometry apparatus **10** is illustrated in FIGS. **1** and **2**. As noted, the probe **14** includes a distal probe tip **18**, the latter being defined by a substantially conical shape including a hollow interior. The heating element, such as an electrical resistor **24**, is secured by epoxy along one circumferential portion of an interior wall **20** of the distal probe tip **18** and the temperature sensing element, such as a thermistor **28**, is also attached using an epoxy or suitable adhesive along another circumferential portion of the interior wall **20**, each of the heating element and temperature sensing element being adjacent to the distal end **19** of the distal probe tip **18**. Sets of electrical leads **32**, **34**, in the form of low gauge copper wires, extend proximally from each of the resistor **24** and thermistor **28**, respectively, and further extend through the body of the probe **14** to a connector on the proximal end (not shown) of the probe **14** for attachment to the device housing (not shown). The electrical leads **32**, **34** provide electrical power to the retained components **24**, **28** and also permit the transmission of signals from the temperature sensing element to the attached device housing (not shown) for processing and display, such as in the course of a typical patient examination.

As shown more clearly in FIG. **2** and during the normal course of use of this thermometry apparatus **100**, the electrical leads **32**, **34** extend away from the interior wall mounted components **24**, **28** with little additional support, especially at the mounted ends of the leads **32**, **34**, and are therefore susceptible to breakage. Premature breakage of the

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electrical leads **32**, **34** frequently requires a complete replacement of the entire thermometry probe **14**, and not just the interior components.

Based in part on the foregoing, there is a general and ongoing need to improve the durability and manufacturability of thermometry assemblies, so as to improve their reliability and increase working life.

Because the temperature sensing element and the heating element are eccentrically mounted to the interior wall of the probe tip, there may also be inconsistencies in terms of heat generation and detection. As a result, there is another general need to improve these characteristics in a thermometry apparatus.

BRIEF DESCRIPTION

According to one aspect, there is provided a temperature measuring apparatus comprising a distal probe tip having an interior and an inner wall. A temperature sensing element is attached to the inner wall. At least one heating element is attached to the inner wall of the housing, the heating element being further connected to a flexible circuit strip.

In one version, the thermometry apparatus can include a shaped mandrel which is initially disposed within the probe tip, the mandrel including at least one feature for securing to the flexible circuit strip during the assembly process. According to one version, the flexible circuit strip includes an opening at a distal end and the mandrel includes a protrusion that is sized to engage the distal opening. In this version, the mandrel is removed from the apparatus prior to final manufacture and test.

In accordance with another aspect, there is described a thermometry apparatus comprising a distal probe tip having a hollow interior. An insulating support is fixedly secured within the interior of the distal probe tip and a temperature sensing element is attached to the insulating support.

In at least one version, the apparatus further comprises at least one heating element that is disposed with the hollow interior of the tip. The at least one heating element can be attached to the insulating support or to a flexible circuit strip.

According to at least one embodiment, a ceramic disc or other suitably shaped planar member is used as the insulating support in which the at least one heater element can be disposed on an outer periphery of one side of the support. According to one preferred version, a pair of heater elements can be disposed on diametrically opposed portions along the outer periphery of the insulating support on a first side thereof. In another version, a heating element can be eliminated entirely from the tip assembly with a temperature sensing element being attached to one side of the support. In at least one embodiment, the heater elements are electrical resistors and the temperature sensing element is a thermistor. In one version, the temperature sensing element can be disposed adjacent the center of the support on a parallel and opposed second surface of the insulating support.

In at least one version, at least one or each of the heating element(s) and the temperature sensing element can be thin-film printed onto respective surfaces of the insulating support.

In accordance with another aspect, there is provided a method for configuring a probe tip to measure temperature, the method comprising the steps of providing an insulating support, fixedly disposing the insulating support within a hollow interior of the probe tip, and securing a temperature sensing element within the interior of the probe tip. In another version, at least one heating element can be further provided. In accordance with the method, the at least one

heating element and the temperature sensing element are attached to opposite surface of the insulating support. In another version, the at least one heating element can be attached to a flexible circuit strip.

Preferably, the support is made from an insulating material and according to at least one embodiment is made from a ceramic. In at least one embodiment, the insulating support includes an outer periphery that substantially matches that of the inner wall of the probe tip in which the substrate can be secured using an interference or press fit. In one such embodiment, the support can be formed as a disc. According to another version, the insulating support need only match a portion of the internal surface of the probe tip and be fixedly attached therein.

According to at least one embodiment, the at least one heating element and the temperature sensing element can be attached to opposing parallel surfaces of the insulating support. In at least one version, at least one or each of the temperature sensing element and the at least one heating element are substrates that are attached to the insulating support by means of thin-film printing. In another version, only the temperature sensing element is attached to the insulating support and heating elements are entirely eliminated from the tip assembly.

In at least one version, a pair of heating elements are disposed along an outer periphery of the insulating support on one side or surface thereof, the pair of heating elements being substantially diametrically opposed and the temperature sensing element being attached at substantially the center of the opposing side or surface of the insulative support. As a result, even circumferential heat generation and heat detection can be advantageously provided.

According to yet another aspect, there is provided a thermometry apparatus comprising a distal probe tip having a hollow interior, and a temperature sensing element disposed within the hollow interior. An insulating support is at least partially mounted within the interior of the distal probe tip; and at least one of the temperature sensing element and the heating element being attached to the support.

According to yet another aspect, there is provided a method of manufacturing a thermometry apparatus in which a thermometry probe is provided, including a distal probe tip made from a thermally conductive material and in which the probe tip has a hollow interior and an interior wall. A temperature sensing element is attached to the interior wall and a heating element is provided as well as a flexible circuit strip having a distal end that is configured to retain the heating element. The heating element is attached to the flexible circuit strip; and the heating element is attached to the interior wall of the tip.

One advantage that is provided by the herein described thermometry apparatus is that of a simpler manufacture in which the insulating support can commonly retain at least one or each of the heating element(s) and temperature sensing element. The foregoing arrangement significantly saves costs in terms of labor and manufacture.

Another advantage provided is that of improved reliability and working life of a thermometry probe, wherein the electrical leads to the temperature sensing element and the heating element(s) are less susceptible to premature breakage.

Yet another advantage is that the disposition of circumferentially disposed heating elements on the insulating support provides uniformity in terms of overall heat generation for the thermometry apparatus, as well as heat detection.

These and other features and advantages will be readily apparent from the following Detailed Description, which should be read in conjunction with the accompanying drawings.

BRIEF DESCRIPTION OF THE DRAWINGS

FIG. 1 is a partial sectioned view of a probe tip for a thermometry apparatus in accordance with the prior art;

FIG. 2 is a perspective view of a probe for a thermometry apparatus including the probe tip of FIG. 1;

FIG. 3 is a partial sectioned view of a thermometry probe tip which is made in accordance with an exemplary embodiment;

FIG. 4 is a perspective view of a portion of an exemplary substrate for use in the probe tip of FIG. 3;

FIG. 5 is a sectioned side elevational view of a probe tip made in accordance with an exemplary embodiment;

FIG. 6 is a bottom facing view of an exemplary substrate for use in a temperature sensing and heating apparatus;

FIG. 7 is a sectioned perspective view of a probe tip of a thermometry apparatus in accordance with another exemplary embodiment;

FIG. 8(a) depicts one side of a flexible circuit strip for use in a thermometry apparatus, such as the apparatus shown in FIG. 7;

FIG. 8(b) depicts the opposite side of the flexible circuit strip depicted in FIG. 8(a); and

FIG. 8(c) is an enlarged view of the distal end of the flexible circuit strip of FIGS. 8(a)-8(b).

DETAILED DESCRIPTION

The following description generally relates to a medical thermometry apparatus and more specifically to embodiments of a distal probe tip that retains at least one heating element and a temperature sensor. It will be readily apparent that other variations and modifications are possible. In addition, certain terms are used throughout this discussion to provide a suitable frame of reference in regard to the accompanying drawings. These terms, which include "upper", "lower", "inner", "outer", "distal", "proximal" and the like are not intended to limit the scope of the inventive concepts, unless specified otherwise.

The drawings are also intended to clearly detail the salient features of the invention. In that regard, the drawings are not necessarily drawn to scale and the reader should not otherwise rely upon the drawings.

Referring to FIG. 3, a sectioned partial view of a probe tip 104 in accordance with an exemplary embodiment is shown, and more specifically a distal end 118 thereof. The distal end 118 of the probe tip 104 is part of a thermometry apparatus 100, similar to that previously described as part of a temperature probe and having features shown in FIG. 2, the tip 104 being tethered to an apparatus housing (not shown), which includes various components, including a processor and signal conditioning electronics. The probe tip 104 according to this exemplary embodiment is defined by a substantially conical configuration having a hollow interior 112 as well as a probe shaft (not shown) extending proximally from the probe tip 104. The probe tip 104 is sized and configured for placement relative to a target of interest, such as the axillary region, under the tongue, the rectum or other suitable area of the patient's body (not shown) from which temperature can be reliably measured. The temperature probe, including the probe tip 104 and the extending probe

shaft, can be manufactured from a stainless steel or from another suitable material possessing a high thermal conductivity.

As shown and in lieu of mounting the various heat generating and detecting components against portions of the interior wall of the probe tip **104**, a support **122** made from a ceramic or other suitable electrically insulating material is fitted within the tip interior **112**. Moreover and in accordance with this specific embodiment, the insulating support **122** is defined by a planar disk having an inner surface **125** and an opposing outer surface **128** in which the insulating support **122** is sized to create a press fit or an interference fit, as installed within the hollow interior **112** of the probe tip **104**. Alternatively, the support **122** can assume other shapes, as discussed herein, in which the insulating support **122** is not necessarily required to assume the precise geometry of the internal surface of the probe tip **104**, provided that the support can be securely attached within the confines of the probe tip **104** and is preferably planar in terms of its construction.

Still referring to FIG. 3 and according to this exemplary embodiment, at least one heating element **130**, such as an electrical resistor, is attached to the inner surface **125** of the insulating support **122** and a temperature sensing element **138** is attached to the outer surface **128** of the insulating support **122**. The temperature sensing element **138** can be, for example, a thermistor or a thermocouple. When mounted and as shown, the outer surface **128** of the mounted insulating support **122** faces the distal end **118** of the probe tip **104** and the opposing inner surface **125** of the support **122** faces the proximal end of the probe. In general, mounting at least one of the above elements **130**, **138** to a fixed component, in this instance the insulating support **122**, provides advantages in terms of heating and manufacturability of the probe tip **104**. In addition, the electrical leads (not shown) of the attached components **130**, **138** can be more reliably secured within the probe tip **104** and therefore much less prone to premature breakage. Alternatively, the heating element **130** can be removed entirely with only the temperature sensing element **138** being attached to the insulating support **122**.

Reference is now made to a more specific exemplary embodiment, as depicted in FIGS. 4-6. Similar parts are herein labeled with the same reference numerals for the sake of clarity. According to this embodiment, a distal tip **104** of a thermometry apparatus **100** includes a hollow interior **112** that is sized to receive an insulating support **122** made from a ceramic or other suitable material. The insulating support **122**, according to this specific embodiment, is defined by a disc-like configuration including an inner surface **125** and an opposing outer surface **128**, as well as an outer periphery **123** that is substantially circular with the exception of two flattened portions **127** that are diametrically opposed to one another. In this version, the flattened portions **127** facilitate a fit within the interior of the distal tip **104** with the inner surface **125** facing the proximal end of the probe and the outer surface **128** facing the distal end **118** of the tip **104**.

As shown in FIG. 6 and according to this exemplary embodiment, a pair of heating elements **130**, such as electrical resistors, are secured to the inner surface **125** of the insulating support **122** at substantially diametrically opposed portions (i.e., approximately 180 degrees apart) that are adjacent the outer periphery **123** of the support **122**. According to this specific version, the heating elements **130** are each thin-film, thereby providing a substrate which can be printed onto the inner surface **125** of the support **122**. Alternatively, a resistor or other heating element (not shown)

could be mounted using epoxy, adhesive or other suitable securing means. A corresponding set of electrical leads **140** each include distal ends **141** that are received within respective openings **144** provided in the insulating support **122**. Each opening **144** includes a bordering electrically conductive area **147** configured to provide electrical power to each of the resistive (heating) elements **130**, as attached to the insulating support **122** as shown more clearly in FIGS. 4-6. The leads **140** are fixedly mounted to the formed openings **144** and placed into electrical contact with the disposed heater elements **130** via the conductive areas **147**.

As shown in FIG. 4, at least one temperature sensing element **138**, such as a thermistor or thermocouple, is mounted to the outer facing surface **128** of the support **122** according to this embodiment. According to the exemplary embodiment and like the heating elements **130**, the temperature sensing element **138** can be a thin-film, which is printed onto the outer surface **128** of the insulating support **122**. Alternatively, however, other securing means such as an epoxy or suitable adhesive can also be utilized. The at least one temperature sensing element **138** can be mounted anywhere along the outer surface **128**. According to this exemplary embodiment, a single temperature sensing element **138** is thin-film printed at about the center of the outer surface **128** and in which a set of electrical leads **140** engage extending conductive portions **139** of the temperature sensing element **138** through a pair of spaced openings **144** provided in the insulating support **122**.

As to manufacture and referring to FIGS. 4-6, the insulating support **122** can be securely attached within the hollow interior **112** of the probe tip **104**. For example, assembly aids, such as grooves or stops, can be provided in the inner wall **116** of the probe tip **104** to assist in the positioning of the insulating support **122**, which is positioned substantially transverse to the center axis **102**, FIG. 5, of the probe tip **104**. According to one version, not shown, a set of spaced portions (not shown) can be provided on the inner surface of the probe tip **104**. Preferably, the temperature sensing element **138** and the heating elements **130** can be secured as substrates using thin-film printing or other suitable means prior to assembly of the insulating support **122** within the interior **112** of the probe tip **104**, and wherein each of the distal ends **141** of the electrical leads **140** can be secured within the openings **144** of the insulating support **122**. Alternatively and as previously discussed, the heating elements **130** can be eliminated entirely from the foregoing assembly with the temperature sensing element **138** being secured to the insulating support **122**.

In operation, the thermometry apparatus **100** is energized in a known manner such as through a switch provided on the exterior of the device housing (not shown), enabling electrical power to be applied to each of the heating elements **130** and the temperature sensing element **138** as the probe tip **104** is brought into substantial proximity with a target of interest (e.g., the axillary area) of a subject (not shown). As previously noted, the probe tip **104** is preheated due to the substantial difference between average body core temperature (98 degrees F.) and that of ambient conditions (65-80 degrees F.) by the application of electrical power (current) to each of the circumferentially disposed heating elements **130** according to this exemplary embodiment. The peripheral and circumferential positioning of the conductive areas **147** of the heating elements **130** at the outer periphery **123** of the insulating support **122** provides uniformity in heat generation of the insulating support **122** to the probe tip **104** and relative to the nominal temperature of the body (not shown) of the subject, this temperature being uniformly detected by

the temperature sensing element **138**. Alternatively and in the absence of heating elements, the foregoing pre-heating step would not be required. Following the above-noted pre-heating step, temperature determinations of the target can be made using the contained temperature sensing element **138** wherein the signals, indicative of a change in temperature (e.g., current) are transmitted along the electrical leads **140** to a processor (not shown) of the thermometry apparatus **100**. The processor can be powered by batteries or other source and is further configured to control the operation of the heating elements and conductive areas. Advantageously and due to the placement of the above components as described, the herein described probe tip design is also more reliable in terms of performance as compared to known thermometry apparatus. That is and at a minimum, heat generation and heat detection is more efficient, uniform and repeatable.

In addition to providing uniformity in terms of heat generation and heat detection, the herein described placements of at least one of the heating and temperature sensing elements **130**, **138** to a single component, such as the insulating support **122**, provides improved stability for each of the mounted electrical leads **140**.

With reference to FIG. 7, another exemplary embodiment of a thermometry apparatus **200** includes an elongate probe body **208** having a substantially conical probe tip **204** that is fabricated from a metallic or other thermally conductive material, such as stainless steel. The probe tip **204** is defined by a hollow interior **212** having an interior circumferential wall **216**. The probe body **208** is only partially shown in this view, wherein the remainder of the probe body and thermometry apparatus **200** is similar to that depicted in FIG. 2 in which the proximal end of the probe is electrically and mechanically connected by a tether to a housing (not shown) containing a processor, a power source and a display.

According to this specific embodiment, a flexible circuit strip **224** having a set of embedded leads is attached to the heating element **230** and provides an electrical attachment point for the heating element **230**. The heating element **230** is attached directly to the interior circumferential wall **216** of the distal probe tip **204**, which allows for the most efficient transfer of heat to the wall **116**. More specifically, the flexible circuit strip **224** is sized to extend over the length of the probe body and to the proximal end thereof. As shown, the flexible circuit strip **224** is secured at a distal end **242** to a radial protrusion **237** of a conical mandrel **239**, the latter being initially placed within the hollow interior **212** of the distal probe tip **104** during an assembly operation. A temperature sensing element **240**, such as a thermistor, is further disposed on an opposing side of the interior circumferential wall **216** of the probe tip **204**.

An exemplary flexible circuit strip **224** is shown in FIGS. 8(a)-8(c). According to this version, the flexible circuit strip **224** is defined by a flat elongate member made from an insulative material, such as polyimide, and having a set of embedded leads formed in a multi-layered structure. The proximal end **246** of the strip **240** includes at least one connective feature for mechanical and electrical attachment to a proximal end connector of the probe (not shown), in which the latter is attached to a device housing (not shown) in a manner similar to that shown in FIG. 2. As shown in FIGS. 8(a) and 8(c), the distal end **242** of the flexible circuit strip **224** includes the attachment surface(s) for the heating element **230**. According to this exemplary embodiment, a pair of attachment pads **252**, **254** are provided in spaced relation to a distal end opening **248**, the latter being sized for reception by the mandrel protrusion **237**.

During an exemplary assembly process, the heating element **230** is applied to the flexible circuit strip **240** and more specifically the leads of the heating element are directly soldered to the attachment pads **252**, **254**. The temperature sensing element **240**, as well as the flexible circuit strip **224** and attached heating element **230** are then loaded onto the assembly mandrel **239** with the flexible circuit strip **224** being attached to the extending protrusion **237** of the mandrel **239** through the distal opening **248** of the flexible circuit strip **224**. A suitable adhesive is applied to the outward facing surfaces of the temperature sensing element **240** and the heating element **230**. The conical probe tip **204** is then slid onto the mandrel **239** and the heating element **230** and the temperature sensing element **240** are adhered to the interior circumferential wall **218** of the probe tip **204**, such as shown in FIG. 7. Once the adhesive is cured, the mandrel **239** can be removed from the interior of the probe tip **204** and discarded. The extending leads **241** of the temperature sensing element **240** can be attached (soldered) to intermediate attachment pads formed **260** on the flexible circuit strip **224**, according to this exemplary embodiment.

In operation, the thermometry apparatus **200** according to this specific embodiment can be energized using a switch or other actuable element on the housing (not shown), which creates the preheating of the probe tip upon the application of electrical power to the heating element **230** from the contained power source (e.g., batteries). Because the electrical leads are embedded within the circuit strip **224**, the leads are not subject to premature breakage. The probe tip **204** is pre-heated wherein the temperature changes induced due to the intended target can be detected by the temperature sensing element **240**, with the resulting signals being transmitted via the flexible circuit strip **224** to the processor (not shown) of the thermometry apparatus **200**.

PARTS LIST FOR FIGS. 1-8(c)

10 thermometry apparatus
14 temperature probe
15 hollow interior
18 distal probe tip
19 distal end
20 interior wall
24 heating element
28 temperature sensing element
32 electrical leads
34 electrical leads
100 thermometry apparatus
102 center axis, probe
104 probe tip
112 interior, hollow
116 inner wall
118 distal end, probe tip
122 insulating support
123 outer periphery, support
125 inner surface, support
127 flattened areas, support
128 outer surface, support
130 heating elements
138 temperature sensing element
139 conductive portions, temperature sensing element
140 electrical leads
141 distal ends, electrical leads
144 openings, spaced
147 conductive areas
200 thermometry apparatus
204 probe tip

208 probe body
 212 distal end
 216 interior circumferential wall
 224 flexible circuit board
 230 heating element
 237 protrusion, distal
 239 mandrel, assembly
 240 temperature sensing element
 241 leads, temperature sensing element
 242 distal end, flexible circuit board
 246 proximal end, flexible circuit board
 248 distal opening, flexible circuit board
 252 resistor pad
 254 resistor pad
 260 pads, attachment intermediate

It will be readily apparent that other variations and modifications are possible in addition to those described in accordance with the inventive concepts of this application and in accordance with the following claims.

We claim:

1. A thermometry apparatus comprising:

a thermometry probe including a distal probe tip made from a thermally conductive material, the distal probe tip having a tip housing defined by a hollow interior, the tip housing having an exterior surface and an opposing interior surface;

a heating element;

a temperature sensing element attached to the interior surface of the tip housing; and

a flexible circuit strip having a distal end retaining the heating element, the heating element being attached to the interior surface of the tip housing and in which the flexible circuit strip is an elongate member made from an electrically insulative material having imbedded leads, the flexible circuit strip further having a proximal end extending to a proximal end of the probe and a distal opening sized for receiving a protrusion of an assembly mandrel disposed in the tip housing, the assembly mandrel being positioned within the hollow interior to retain and initially position the flexible circuit strip, heating element and temperature sensing

element relative to the interior surface of the tip housing and wherein the assembly mandrel is removable after the flexible circuit strip, heating element and temperature sensing element are secured within the tip housing.

2. The thermometry apparatus of claim 1, wherein the heating element and the temperature sensing element are disposed on opposing sides of the interior surface of the tip housing.

3. The thermometry apparatus of claim 1, in which the distal probe tip and the assembly mandrel are conical.

4. The thermometry apparatus of claim 1, in which the proximal end of the flexible circuit strip is configured for mechanical and electrical attachment to a proximal end connector of the probe.

5. The thermometry apparatus as recited in claim 1, in which the temperature sensing element is at least one of a thermistor and a thermocouple.

6. The thermometry apparatus of claim 1, in which the distal end of the flexible circuit strip includes an attachment surface for the heating element.

7. The thermometry apparatus of claim 1, wherein the flexible circuit strip includes a pair of attachment pads provided in spaced relation to the distal opening.

8. The thermometry apparatus of claim 7, in which leads of the heating element are soldered to the attachment pads.

9. The thermometry apparatus of claim 1, wherein the flexible circuit strip includes intermediate attachment pads and in which extending leads of the temperature sensing element are soldered to the intermediate attachment pads.

10. The thermometry apparatus of claim 1, in which the flexible circuit strip is made from polyimide.

11. The thermometry apparatus of claim 4, in which the proximal end of the flexible circuit strip includes a connective feature for mechanical and electrical attachment to a proximal end connector of the thermometry probe.

12. The thermometry apparatus of claim 1, in which the flexible circuit strip, including the imbedded leads, is defined by a multi-layered structure.

* * * * *

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摘要(译)

测温装置包括具有中空内部的远端探针尖端。绝缘支架至少部分地设置在远端探针尖端的内部。绝缘支撑件构造接收至少一个加热元件和至少一个温度感测元件中的至少一个。根据一个版本, 绝缘支撑件是柔性电路条, 所述柔性电路条被构造接收至少一个加热元件以保护引线免受损坏和过早断裂。

200

